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What is "Embedded - Microcontrollers"?

"Embedded - Microcontrollers" refer to small, integrated circuits designed to perform specific tasks within larger systems. These microcontrollers are essentially compact computers on a single chip, containing a processor core, memory, and programmable input/output peripherals. They are called "embedded" because they are embedded within electronic devices to control various functions, rather than serving as standalone computers. Microcontrollers are crucial in modern electronics, providing the intelligence and control needed for a wide range of applications.

Applications of "<u>Embedded - Microcontrollers</u>"

Details	
Product Status	Obsolete
Core Processor	80C51
Core Size	8-Bit
Speed	30/20MHz
Connectivity	UART/USART
Peripherals	POR
Number of I/O	32
Program Memory Size	-
Program Memory Type	ROMIess
EEPROM Size	-
RAM Size	256 x 8
Voltage - Supply (Vcc/Vdd)	2.7V ~ 5.5V
Data Converters	-
Oscillator Type	Internal
Operating Temperature	-40°C ~ 85°C (TA)
Mounting Type	Surface Mount
Package / Case	44-LCC (J-Lead)
Supplier Device Package	44-PLCC (16.6x16.6)
Purchase URL	https://www.e-xfl.com/product-detail/microchip-technology/at80c32x2-slrul



Mnemonic Pin Number		Туре	Name and Function				
	DIL	LCC	VQFP 1.4				
V _{SS}	20	22	16	I	Ground: 0V reference		
Vss1		1	39	I	Optional Ground: Contact the Sales Office for ground connection.		
V _{CC}	40	44	38	I	Power Supply: This is the power supply voltage for normal, idle and power-down operation		
P0.0-P0.7	39- 32	43- 36	37-30	I/O	Port 0: Port 0 is an open-drain, bidirectional I/O port. Port 0 pins that have 1s written to them float and can be used as high impedance inputs.Port 0 pins must be polarized to Vcc or Vss in order to prevent any parasitic current consumption. Port 0 is also the multiplexed low-order address and data bus during access to external program and data memory. In this application, it uses strong internal pull-up when emitting 1s. Port 0 also inputs the code bytes during EPROM programming. External pull-ups are required during program		
					verification during which P0 outputs the code bytes.		
P1.0-P1.7	1-8	2-9	40-44 1-3	I/O	Port 1: Port 1 is an 8-bit bidirectional I/O port with internal pull-ups. Port 1 pins that have 1s written to them are pulled high by the internal pull-ups and can be used as inputs. As		
					inputs, Port 1 pins that are externally pulled low will source current because of the internal pull-ups. Port 1 also receives the low-order address byte during memory programming and verification. Alternate functions for Port 1 include:		
	1	2	40	I/O	T2 (P1.0): Timer/Counter 2 external count input/Clockout		
	2	3	41	I	T2EX (P1.1): Timer/Counter 2 Reload/Capture/Direction Control		
P2.0-P2.7	21- 28	24- 31	18-25	I/O	Port 2: Port 2 is an 8-bit bidirectional I/O port with internal pull-ups. Port 2 pins that have 1s written to them are pulled high by the internal pull-ups and can be used as inputs. As		
					inputs, Port 2 pins that are externally pulled low will source current because of the internal pull-ups. Port 2 emits the high-order address byte during fetches from external program memory and during accesses to external data memory that use 16-bit addresses (MOVX atDPTR). In this application, it uses strong internal pull-ups emitting 1s. During accesses to external data memory that use 8-bit addresses (MOVX atRi), port 2 emits the contents of the P2 SFR. Some Port 2 pins receive the high order address bits during EPROM programming and verification: P2.0 to P2.4		
P3.0-P3.7	10- 17	11, 13- 19	5, 7-13	I/O	Port 3: Port 3 is an 8-bit bidirectional I/O port with internal pull-ups. Port 3 pins that have 1s written to them are pulled high by the internal pull-ups and can be used as inputs. As inputs, Port 3 pins that are externally pulled low will source		
					current because of the internal pull-ups. Port 3 also serves the special features of the 80C51 family, as listed below.		
	10	11	5	I	RXD (P3.0): Serial input port		
	11	13	7	0	TXD (P3.1): Serial output port		
	12	14	8	I	INTO (P3.2): External interrupt 0		

Mnemonic Pir		Pin Number			Name and Function			
	DIL LCC VQFP							
	13	15	9	I	INT1 (P3.3): External interrupt 1			
	14	16	10	I	T0 (P3.4): Timer 0 external input			
	15	17	11	I	T1 (P3.5): Timer 1 external input			
	16	18	12	0	WR (P3.6): External data memory write strobe			
	17	19	13	0	RD (P3.7): External data memory read strobe			
Reset	9	10	4	I	Reset: A high on this pin for two machine cycles while the oscillator is running, resets the device. An internal diffused resistor to V _{SS} permits a power-on reset using only an external capacitor to V _{CC} .			
ALE/PROG	30	33	27	O (I)	Address Latch Enable/Program Pulse: Output pulse for latching the low byte of the address during an access to external memory. In normal operation, ALE is emitted at a constant rate of 1/6 (1/3 in X2 mode) the oscillator frequency, and can be used for external timing or clocking. Note that one ALE pulse is skipped during each access to external data memory. This pin is also the program pulse input (PROG) during EPROM programming. ALE can be disabled by setting SFR's AUXR.0 bit. With this bit set, ALE will be inactive during internal fetches.			
PSEN	29	32	26	0	Program Store ENable: The read strobe to external program memory. When executing code from the external program memory, PSEN is activated twice each machine cycle, except that two PSEN activations are skipped during each access to external data memory. PSEN is not activated during fetches from internal program memory.			
EA/V _{PP}	31	35	29	I	External Access Enable/Programming Supply Voltage: EA must be externally held low to enable the device to fetch code from external program memory locations 0000H and 3FFFH (RB) or 7FFFH (RC), or FFFFH (RD). If EA is held high, the device executes from internal program memory unless the program counter contains an address greater than 3FFFH (RB) or 7FFFH (RC) EA must be held low for ROMless devices. This pin also receives the 12.75V programming supply voltage (V _{PP}) during EPROM programming. If security level 1 is programmed, EA will be internally latched on Reset.			
XTAL1	19	21	15	ı	Crystal 1: Input to the inverting oscillator amplifier and input to the internal clock generator circuits.			
XTAL2	18	20	14	0	Crystal 2: Output from the inverting oscillator amplifier			





Dual Data Pointer Register (Ddptr)

The additional data pointer can be used to speed up code execution and reduce code size in a number of ways.

The dual DPTR structure is a way by which the chip will specify the address of an external data memory location. There are two 16-bit DPTR registers that address the external memory, and a single bit called

DPS = AUXR1/bit0 (See Table 5.) that allows the program code to switch between them (Refer to Figure 3).

Figure 3. Use of Dual Pointer

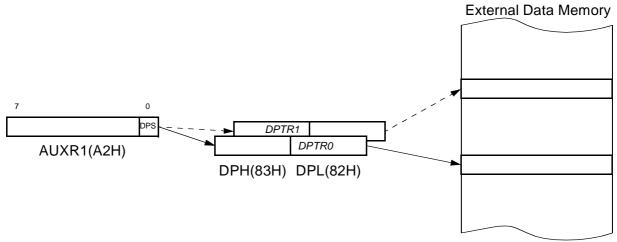


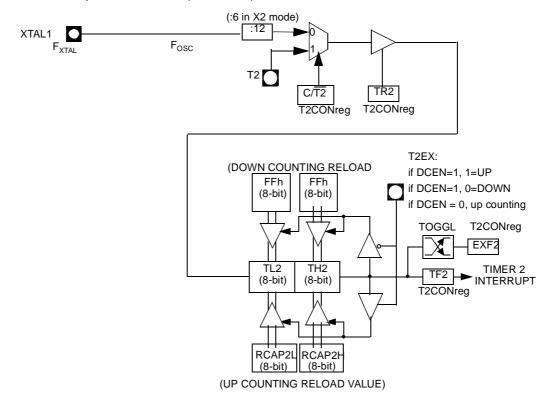
Table 4. AUXR1: Auxiliary Register 1

7	6	5	4	3	2	1	0
-	-	-	-	GF3	0	-	DPS

Bit Number	Bit Mnemonic	Description					
7	-	Reserved The value read from this bit is indeterminate. Do not set this bit.					
6	-	Reserved The value read from this bit is indeterminate. Do not set this bit.					
5	-	Reserved The value read from this bit is indeterminate. Do not set this bit.					
4	Reserved The value read from this bit is indeterminate. Do not set this bit.						
3	GF3	This bit is a general purpose user flag					
2	0	0 Reserved Always stuck at 0					
1	-	Reserved The value read from this bit is indeterminate. Do not set this bit.					
0	DPS	Data Pointer Selection Clear to select DPTR0. Set to select DPTR1.					

Reset Value = XXXX XXX0
Not bit addressable

Figure 4. Auto-reload Mode Up/Down Counter (DCEN = 1)



Programmable Clock-output

In the clock-out mode, timer 2 operates as a 50%-duty-cycle, programmable clock generator (See Figure 5) . The input clock increments TL2 at frequency $F_{\rm OSC}/2$. The timer repeatedly counts to overflow from a loaded value. At overflow, the contents of RCAP2H and RCAP2L registers are loaded into TH2 and TL2. In this mode, timer 2 overflows do not generate interrupts. The formula gives the clock-out frequency as a function of the system oscillator frequency and the value in the RCAP2H and RCAP2L registers :

$$Clock - OutFrequency = \frac{F_{osc}}{4 \times (65536 - RCAP2H/RCAP2L)}$$

For a 16 MHz system clock, timer 2 has a programmable frequency range of 61 Hz $(F_{OSC}/2^{16})$ to 4 MHz $(F_{OSC}/4)$. The generated clock signal is brought out to T2 pin (P1.0).

Timer 2 is programmed for the clock-out mode as follows:

- Set T2OE bit in T2MOD register.
- Clear C/T2 bit in T2CON register.
- Determine the 16-bit reload value from the formula and enter it in RCAP2H/RCAP2L registers.
- Enter a 16-bit initial value in timer registers TH2/TL2. It can be the same as the reload value or a different one depending on the application.
- To start the timer, set TR2 run control bit in T2CON register.

It is possible to use timer 2 as a baud rate generator and a clock generator simultaneously. For this configuration, the baud rates and clock frequencies are not independent since both functions use the values in the RCAP2H and RCAP2L registers.



Table 5. T2CON Register

T2CON - Timer 2 Control Register (C8h)

TF2 EXF2 RCLK TCLK EXEN2 TR2 C/T2# CP/RL2#

3

Bit Number	Bit Mnemonic	Description
7	TF2	Timer 2 overflow Flag Must be cleared by software. Set by hardware on timer 2 overflow, if RCLK = 0 and TCLK = 0.
6	EXF2	Timer 2 External Flag Set when a capture or a reload is caused by a negative transition on T2EX pin if EXEN2=1. When set, causes the CPU to vector to timer 2 interrupt routine when timer 2 interrupt is enabled. Must be cleared by software. EXF2 doesn't cause an interrupt in Up/down counter mode (DCEN = 1)
5	RCLK	Receive Clock bit Clear to use timer 1 overflow as receive clock for serial port in mode 1 or 3. Set to use timer 2 overflow as receive clock for serial port in mode 1 or 3.
4	TCLK	Transmit Clock bit Clear to use timer 1 overflow as transmit clock for serial port in mode 1 or 3. Set to use timer 2 overflow as transmit clock for serial port in mode 1 or 3.
3	EXEN2	Timer 2 External Enable bit Clear to ignore events on T2EX pin for timer 2 operation. Set to cause a capture or reload when a negative transition on T2EX pin is detected, if timer 2 is not used to clock the serial port.
2	TR2	Timer 2 Run control bit Clear to turn off timer 2. Set to turn on timer 2.
1	C/T2#	Timer/Counter 2 select bit Clear for timer operation (input from internal clock system: F _{OSC}). Set for counter operation (input from T2 input pin, falling edge trigger). Must be 0 for clock out mode.
0	CP/RL2#	Timer 2 Capture/Reload bit If RCLK=1 or TCLK=1, CP/RL2# is ignored and timer is forced to Auto-reload on timer 2 overflow. Clear to Auto-reload on timer 2 overflows or negative transitions on T2EX pin if EXEN2=1. Set to capture on negative transitions on T2EX pin if EXEN2=1.

Reset Value = 0000 0000b Bit addressable



Exit from power-down by reset redefines all the SFRs, exit from power-down by external interrupt does no affect the SFRs.

Exit from power-down by either reset or external interrupt does not affect the internal RAM content.

Note:

If idle mode is activated with power-down mode (IDL and PD bits set), the exit sequence is unchanged, when execution is vectored to interrupt, PD and IDL bits are cleared and idle mode is not entered.

Table 15. The State of Ports During Idle and Power-down Modes

Mode	Program Memory	ALE	PSEN	PORT0	PORT1	PORT2	PORT3
Idle	Internal	nal 1		Port Data ⁽¹⁾	Port Data	Port Data	Port Data
Idle	External	1	1	Floating	Port Data	Address	Port Data
Power Down	Internal	0	0 Port Data ⁽¹⁾		Port Data	Port Data	Port Data
Power Down	External	0	0	Floating	Port Data	Port Data	Port Data

Note: 1. Port 0 can force a "zero" level. A "one" will leave port floating.





EPROM Structure

The TS87C52X2 is divided in two different arrays:

- · the code array: 8 Kbytes
- the encryption array: 64 bytes

In addition a third non programmable array is implemented:

the signature array: 4 bytes

EPROM Lock System

The program Lock system, when programmed, protects the on-chip program against software piracy.

Encryption Array

Within the EPROM array are 64 bytes of encryption array that are initially unprogrammed (all FF's). Every time a byte is addressed during program verify, 6 address lines are used to select a byte of the encryption array. This byte is then exclusive-NOR'ed (XNOR) with the code byte, creating an encrypted verify byte. The algorithm, with the encryption array in the unprogrammed state, will return the code in its original, unmodified form.

When using the encryption array, one important factor needs to be considered. If a byte has the value FFh, verifying the byte will produce the encryption byte value. If a large block (>64 bytes) of code is left unprogrammed, a verification routine will display the content of the encryption array. For this reason all the unused code bytes should be programmed with random values. This will ensure program protection.

Program Lock Bits

The three lock bits, when programmed according to Table 1., will provide different level of protection for the on-chip code and data.

Pr	ogram Lo	ock Bits		
Security level	·		LB3	Protection Description
1	U	U	U	No program lock features enabled. Code verify will still be encrypted by the encryption array if programmed. MOVC instruction executed from external program memory returns non encrypted data.
2	Р	U	U	MOVC instruction executed from external program memory are disabled from fetching code bytes from internal memory, EA is sampled and latched on reset, and further programming of the EPROM is disabled.
3	U	Р	U	Same as 2, also verify is disabled.
4	U	U	Р	Same as 3, also external execution is disabled.

U: unprogrammed P: programmed

WARNING: Security level 2 and 3 should only be programmed after EPROM and Core verification.

Signature Bytes

The TS80/87C52X2 contains 4 factory programmed signatures bytes. To read these bytes, perform the process described in section 9.

EPROM Programming

Set-up modes

In order to program and verify the EPROM or to read the signature bytes, the TS87C52X2 is placed in specific set-up modes (See Figure 11.).

Control and program signals must be held at the levels indicated in Table 35.

Definition of terms

Address Lines: P1.0-P1.7, P2.0-P2.4 respectively for A0-A12

Data Lines: P0.0-P0.7 for D0-D7

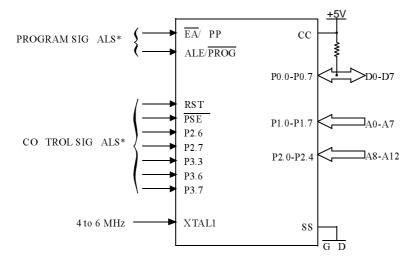
Control Signals: RST, PSEN, P2.6, P2.7, P3.3, P3.6, P3.7.

Program Signals: ALE/PROG, EA/VPP.

Table 20. EPROM Set-up Modes

Mode	RST	PSEN	ALE/ PROG	EA/ VPP	P2.6	P2.7	P3.3	P3.6	P3.7
Program Code data	1	0	T.	12.75V	0	1	1	1	1
Verify Code data	1	0	1	1	0		0	1	1
Program Encryption Array Address 0-3Fh	1	0	ъ	12.75V	0	1	1	0	1
Read Signature Bytes	1	0	1	1	0		0	0	0
Program Lock bit 1	1	0	П	12.75V	1	1	1	1	1
Program Lock bit 2	1	0	ப	12.75V	1	1	1	0	0
Program Lock bit 3	1	0	ъ	12.75V	1	0	1	1	0

Figure 11. Set-Up Modes Configuration



^{*} See Table 31. for proper value on these inputs



 $12,000 \,\mu\text{W/cm}^2$ rating for 30 minutes, at a distance of about 25 mm, should be sufficient. An exposure of 1 hour is recommended with most of standard erasers.

Erasure of the EPROM begins to occur when the chip is exposed to light with wavelength shorter than approximately 4,000 Å. Since sunlight and fluorescent lighting have wavelengths in this range, exposure to these light sources over an extended time (about 1 week in sunlight, or 3 years in room-level fluorescent lighting) could cause inadvertent erasure. If an application subjects the device to this type of exposure, it is suggested that an opaque label be placed over the window.

Signature Bytes

The TS80/87C52X2 has four signature bytes in location 30h, 31h, 60h and 61h. To read these bytes follow the procedure for EPROM verify but activate the control lines provided in Table 31. for Read Signature Bytes. Table 35. shows the content of the signature byte for the TS80/87C52X2.

Table 21. Signature Bytes Content

Location	Contents	Comment
30h	58h	Manufacturer Code: Atmel
31h	57h	Family Code: C51 X2
60h	2Dh	Product name: TS80C52X2
60h	ADh	Product name:TS87C52X2
60h	20h	Product name: TS80C32X2
61h	FFh	Product revision number





Electrical Characteristics

Absolute Maximum Ratings⁽¹⁾

Ambiant Temperature Under Bias:	
C = commercial	0°C to 70°C
I = industrial	40°C to 85°C
Storage Temperature	65°C to + 150°C
Voltage on V _{CC} to V _{SS}	0.5V to + 7 V
Voltage on V _{PP} to V _{SS}	
Voltage on Any Pin to V _{SS}	0.5V to V _{CC} + 0.5V
Power Dissipation	1 W ⁽²⁾

- Notes: 1. Stresses at or above those listed under "Absolute Maximum Ratings" may cause permanent damage to the device. This is a stress rating only and functional operation of the device at these or any other conditions above those indicated in the operational sections of this specification is not implied. Exposure to absolute maximum rating conditions may affect device reliability.
 - 2. This value is based on the maximum allowable die temperature and the thermal resistance of the package.

Power Consumption Measurement

Since the introduction of the first C51 devices, every manufacturer made operating Icc measurements under reset, which made sense for the designs were the CPU was running under reset. In Atmel new devices, the CPU is no more active during reset, so the power consumption is very low but is not really representative of what will happen in the customer system. That's why, while keeping measurements under Reset, Atmel presents a new way to measure the operating Icc:

Using an internal test ROM, the following code is executed:

SJMP Label (80 FE) Label:

Ports 1, 2, 3 are disconnected, Port 0 is tied to FFh, EA = Vcc, RST = Vss, XTAL2 is not connected and XTAL1 is driven by the clock.

This is much more representative of the real operating lcc.

DC Parameters for Standard Voltage

Ta = 0°C to +70°C; V_{SS} = 0 V; V_{CC} = 5V \pm 10%; F = 0 to 40 MHz. Ta = -40°C to +85°C; V_{SS} = 0 V; V_{CC} = 5V \pm 10%; F = 0 to 40 MHz.

Table 22. DC Parameters in Standard Voltage

Symbol	Parameter	Min	Тур	Max	Unit	Test Conditions
V _{IL}	Input Low Voltage	-0.5		0.2 V _{CC} - 0.1	V	
V _{IH}	Input High Voltage except XTAL1, RST	0.2 V _{CC} + 0.9		V _{CC} + 0.5	V	
V _{IH1}	Input High Voltage, XTAL1, RST	0.7 V _{CC}		V _{CC} + 0.5	V	
V _{OL}	Output Low Voltage, ports 1, 2, 3 ⁽⁶⁾			0.3 0.45 1.0	V V V	$I_{OL} = 100 \ \mu A^{(4)}$ $I_{OL} = 1.6 \ mA^{(4)}$ $I_{OL} = 3.5 \ mA^{(4)}$
V _{OL1}	Output Low Voltage, port 0 (6)			0.3 0.45 1.0	V V V	$I_{OL} = 200 \ \mu A^{(4)}$ $I_{OL} = 3.2 \ mA^{(4)}$ $I_{OL} = 7.0 \ mA^{(4)}$
V _{OL2}	Output Low Voltage, ALE, PSEN			0.3 0.45 1.0	V V V	$I_{OL} = 100 \ \mu A^{(4)}$ $I_{OL} = 1.6 \ mA^{(4)}$ $I_{OL} = 3.5 \ mA^{(4)}$



DC Parameters for Low Voltage

TA = 0°C to +70°C; V_{SS} = 0 V; V_{CC} = 2.7 V to 5.5V; F = 0 to 30 MHz. TA = -40°C to +85°C; V_{SS} = 0 V; V_{CC} = 2.7 V to 5.5V; F = 0 to 30 MHz.

Table 23. DC Parameters for Low Voltage

Symbol	Parameter	Min	Тур	Max	Unit	Test Conditions
V _{IL}	Input Low Voltage	-0.5		0.2 V _{CC} - 0.1	V	
V _{IH}	Input High Voltage except XTAL1, RST	0.2 V _{CC} + 0.9		V _{CC} + 0.5	V	
V _{IH1}	Input High Voltage, XTAL1, RST	0.7 V _{CC}		V _{CC} + 0.5	V	
V _{OL}	Output Low Voltage, ports 1, 2, 3 (6)			0.45	V	$I_{OL} = 0.8 \text{ mA}^{(4)}$
V _{OL1}	Output Low Voltage, port 0, ALE, PSEN (6)			0.45	V	I _{OL} = 1.6 mA ⁽⁴⁾
V _{OH}	Output High Voltage, ports 1, 2, 3	0.9 V _{CC}			V	I _{OH} = -10 μA
V _{OH1}	Output High Voltage, port 0, ALE, PSEN	0.9 V _{CC}			V	I _{OH} = -40 μA
I _{IL}	Logical 0 Input Current ports 1, 2 and 3			-50	μΑ	Vin = 0.45V
I _{LI}	Input Leakage Current			±10	μΑ	0.45V < Vin < V _{CC}
I _{TL}	Logical 1 to 0 Transition Current, ports 1, 2, 3			-650	μΑ	Vin = 2.0 V
R _{RST}	RST Pulldown Resistor	50	90 (5)	200	kΩ	
CIO	Capacitance of I/O Buffer			10	pF	Fc = 1 MHz Ta = 25°C
I _{PD}	Power Down Current		20 ⁽⁵⁾ 10 ⁽⁵⁾	50 30	μА	$V_{CC} = 2.0 \text{ V to } 5.5 \text{V}^{(3)}$ $V_{CC} = 2.0 \text{ V to } 3.3 \text{ V}^{(3)}$
I _{CC} under RESET	Power Supply Current Maximum values, X1 mode: (7)			1 + 0.2 Freq (MHz) at12MHz 3.4 at16MHz 4.2	mA	$V_{CC} = 3.3 V^{(1)}$
I _{CC} operating	Power Supply Current Maximum values, X1 mode: (7)			1 + 0.3 Freq (MHz) at12MHz 4.6 at16MHz 5.8	mA	$V_{CC} = 3.3 V^{(8)}$
I _{CC} idle	Power Supply Current Maximum values, X1 mode: (7)			0.15 Freq (MHz) + 0.2 at12MHz 2 at16MHz 2.6	mA	$V_{CC} = 3.3 V^{(2)}$

Notes: 1. I_{CC} under reset is measured with all output pins disconnected; XTAL1 driven with T_{CLCH} , $T_{CHCL} = 5$ ns (see Figure 17.), $V_{IL} = V_{SS} + 0.5V$,

 $V_{IH} = V_{CC} - 0.5V$; XTAL2 N.C.; $\overline{EA} = RST = Port \ 0 = V_{CC}$. I_{CC} would be slightly higher if a crystal oscillator used..

- 2. Idle I_{CC} is measured with all out<u>put</u> pins disconnected; XTAL1 driven with T_{CLCH}, T_{CHCL} = 5 ns, V_{IL} = V_{SS} + 0.5V, V_{IH} = V_{CC} 0.5V; XTAL2 N.C; Port 0 = V_{CC}; EA = RST = V_{SS} (see Figure 15.).
- 3. Power Down I_{CC} is measured with all output pins disconnected; EA = V_{SS}, PORT 0 = V_{CC}; XTAL2 NC.; RST = V_{SS} (see Figure 16.).
- 4. Capacitance loading on Ports 0 and 2 may cause spurious noise pulses to be superimposed on the V_{OL}s of ALE and Ports 1 and 3. The noise is due to external bus capacitance discharging into the Port 0 and Port 2 pins when these pins make 1 to 0 transitions during bus operation. In the worst cases (capacitive loading 100pF), the noise pulse on the ALE line may exceed 0.45V with maxi V_{OL} peak 0.6V. A Schmitt Trigger use is not necessary.
- 5. Typicals are based on a limited number of samples and are not guaranteed. The values listed are at room temperature and 5V.
- Under steady state (non-transient) conditions, I_{OL} must be externally limited as follows: Maximum I_{OL} per port pin: 10 mA Maximum I_{OL} per 8-bit port:

Port 0: 26 mA

Ports 1, 2 and 3: 15 mA

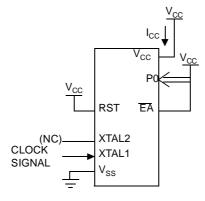
Maximum total I_{OL} for all output pins: 71 mA

If I_{OL} exceeds the test condition, V_{OL} may exceed the related specification. Pins are not guaranteed to sink current greater than the listed test conditions.

- 7. For other values, please contact your sales office.
- 8. Operating I_{CC} is measured with all output pins disconnected; XTAL1 driven with T_{CLCH} , T_{CHCL} = 5 ns (see Figure 17.), V_{IL} = V_{SS} + 0.5V,

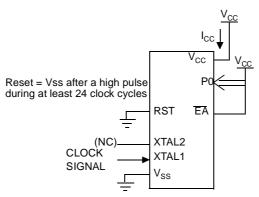
 $V_{IH} = V_{CC} - 0.5V$; XTAL2 N.C.; $\overline{EA} = Port \ 0 = V_{CC}$; RST = V_{SS} . The internal ROM runs the code 80 FE (label: SJMP label). I_{CC} would be slightly higher if a crystal oscillator is used. Measurements are made with OTP products when possible, which is the worst case.

Figure 13. I_{CC} Test Condition, under reset



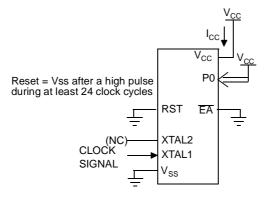
All other pins are disconnected.

Figure 14. Operating I_{CC} Test Condition



All other pins are disconnected.

Figure 15. I_{CC} Test Condition, Idle Mode



All other pins are disconnected.





Table 27. AC Parameters for Fix Clock

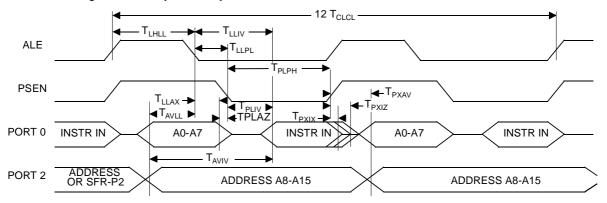
Speed		M MHz	X2 n 30 l 60 l	V node MHz MHz uiv.	stan mod	V dard le 40 Hz	X2 n 20 l 40 l	L node MHz MHz uiv.	stan mo	L dard ode MHz	Units
Symbol	Min	Max	Min	Max	Min	Max	Min	Max	Min	Max	
Т	25		33		25		50		33		ns
T _{LHLL}	40		25		42		35		52		ns
T _{AVLL}	10		4		12		5		13		ns
T _{LLAX}	10		4		12		5		13		ns
T _{LLIV}		70		45		78		65		98	ns
T _{LLPL}	15		9		17		10		18		ns
T _{PLPH}	55		35		60		50		75		ns
T _{PLIV}		35		25		50		30		55	ns
T _{PXIX}	0		0		0		0		0		ns
T _{PXIZ}		18		12		20		10		18	ns
T _{AVIV}		85		53		95		80		122	ns
T _{PLAZ}		10		10		10		10		10	ns

Table 28. AC Parameters for a Variable Clock: derating formula

Symbol	Туре	Standard Clock	X2 Clock	-M	-V	-L	Units
T _{LHLL}	Min	2 T - x	T - x	10	8	15	ns
T _{AVLL}	Min	T - x	0.5 T - x	15	13	20	ns
T _{LLAX}	Min	T - x	0.5 T - x	15	13	20	ns
T _{LLIV}	Max	4 T - x	2 T - x	30	22	35	ns
T _{LLPL}	Min	T - x	0.5 T - x	10	8	15	ns
T _{PLPH}	Min	3 T - x	1.5 T - x	20	15	25	ns
T _{PLIV}	Max	3 T - x	1.5 T - x	40	25	45	ns
T _{PXIX}	Min	х	х	0	0	0	ns
T _{PXIZ}	Max	T - x	0.5 T - x	7	5	15	ns
T _{AVIV}	Max	5 T - x	2.5 T - x	40	30	45	ns
T _{PLAZ}	Max	х	х	10	10	10	ns

External Program Memory Read Cycle

Figure 18. External Program Memory Read Cycle



External Data Memory Characteristics

 Table 29.
 Symbol Description

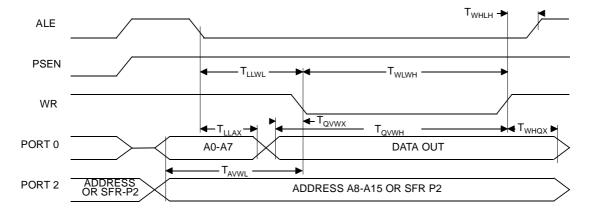
Symbol	Parameter
T _{RLRH}	RD Pulse Width
T _{WLWH}	WR Pulse Width
T _{RLDV}	RD to Valid Data In
T _{RHDX}	Data Hold After RD
T _{RHDZ}	Data Float After RD
T _{LLDV}	ALE to Valid Data In
T _{AVDV}	Address to Valid Data In
T _{LLWL}	ALE to WR or RD
T _{AVWL}	Address to WR or RD
T _{QVWX}	Data Valid to WR Transition
T _{QVWH}	Data set-up to WR High
T _{WHQX}	Data Hold After WR
T _{RLAZ}	RD Low to Address Float
T _{WHLH}	RD or WR High to ALE high

 Table 31. AC Parameters for a Variable Clock: Derating Formula

Symbol	Туре	Standard Clock	X2 Clock	-M	-V	-L	Units
T _{RLRH}	Min	6 T - x	3 T - x	20	15	25	ns
T _{WLWH}	Min	6 T - x	3 T - x	20	15	25	ns
T _{RLDV}	Max	5 T - x	2.5 T - x	25	23	30	ns
T _{RHDX}	Min	х	х	0	0	0	ns
T _{RHDZ}	Max	2 T - x	T - x	20	15	25	ns
T _{LLDV}	Max	8 T - x	4T -x	40	35	45	ns
T _{AVDV}	Max	9 T - x	4.5 T - x	60	50	65	ns
T _{LLWL}	Min	3 T - x	1.5 T - x	25	20	30	ns
T _{LLWL}	Max	3 T + x	1.5 T + x	25	20	30	ns
T _{AVWL}	Min	4 T - x	2 T - x	25	20	30	ns
T _{QVWX}	Min	T - x	0.5 T - x	15	10	20	ns
T _{QVWH}	Min	7 T - x	3.5 T - x	15	10	20	ns
T _{WHQX}	Min	T - x	0.5 T - x	10	8	15	ns
T _{RLAZ}	Max	х	х	0	0	0	ns
T _{WHLH}	Min	T - x	0.5 T - x	15	10	20	ns
T _{WHLH}	Max	T + x	0.5 T + x	15	10	20	ns

External Data Memory Write Cycle

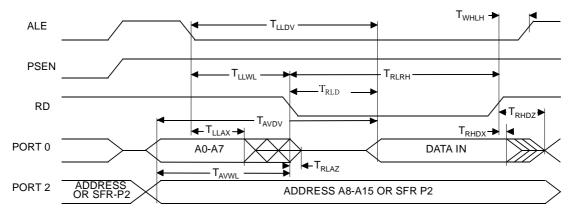
Figure 19. External Data Memory Write Cycle





External Data Memory Read Cycle

Figure 20. External Data Memory Read Cycle



Serial Port Timing - Shift Register Mode

Table 32. Symbol Description

Symbol	Parameter
T _{XLXL}	Serial port clock cycle time
T _{QVHX}	Output data set-up to clock rising edge
T _{XHQX}	Output data hold after clock rising edge
T _{XHDX}	Input data hold after clock rising edge
T _{XHDV}	Clock rising edge to input data valid

Table 33. AC Parameters for a Fix Clock

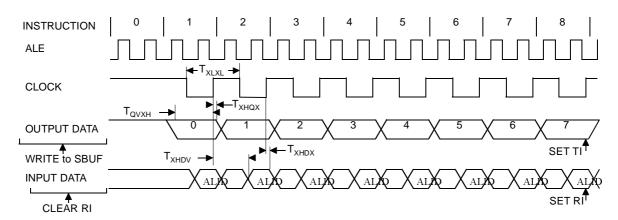
Speed		M MHz	X2 m 30 l	V node MHz MHz uiv.	stan mod	V dard le 40 Hz	X2 m 20 f	L node MHz MHz uiv.	mo	L dard ode MHz	Units
Symbol	Min	Max	Min	Max	Min	Max	Min	Max	Min	Max	
T _{XLXL}	300		200		300		300		400		ns
T _{QVHX}	200		117		200		200		283		ns
T _{XHQX}	30		13		30		30		47		ns
T _{XHDX}	0		0		0		0		0		ns
T _{XHDV}		117		34		117		117		200	ns

Table 34. AC Parameters for a Variable Clock: Derating Formula

Symbol	Туре	Standard Clock	X2 Clock	-M	-V	-L	Units
T _{XLXL}	Min	12 T	6 T				ns
T _{QVHX}	Min	10 T - x	5 T - x	50	50	50	ns
T _{XHQX}	Min	2 T - x	T - x	20	20	20	ns
T _{XHDX}	Min	х	х	0	0	0	ns
T _{XHDV}	Max	10 T - x	5 T- x	133	133	133	ns

Shift Register Timing Waveforms

Figure 21. Shift Register Timing Waveforms





EPROM Programming and Verification Characteristics

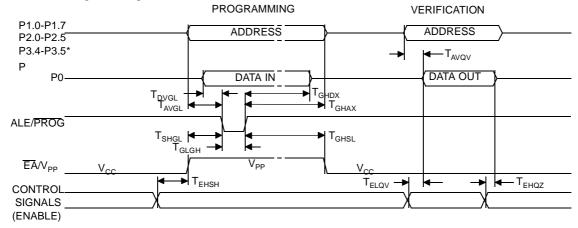
 T_A = 21°C to 27°C; V_{SS} = 0V; V_{CC} = 5V \pm 10% while programming. V_{CC} = operating range while verifying.

Table 35. EPROM Programming Parameters

Symbol	Parameter	Min	Max	Units
V _{PP}	Programming Supply Voltage	12.5	13	V
I _{PP}	Programming Supply Current		75	mA
1/T _{CLCL}	Oscillator Frquency	4	6	MHz
T _{AVGL}	Address Setup to PROG Low	48 T _{CLCL}		
T _{GHAX}	Adress Hold after PROG	48 T _{CLCL}		
T _{DVGL}	Data Setup to PROG Low	48 T _{CLCL}		
T _{GHDX}	Data Hold after PROG	48 T _{CLCL}		
T _{EHSH}	(Enable) High to V _{PP}	48 T _{CLCL}		
T _{SHGL}	V _{PP} Setup to PROG Low	10		μs
T _{GHSL}	V _{PP} Hold after PROG	10		μs
T _{GLGH}	PROG Width	90	110	μs
T _{AVQV}	Address to Valid Data		48 T _{CLCL}	
T _{ELQV}	ENABLE Low to Data Valid		48 T _{CLCL}	
T _{EHQZ}	Data Float after ENABLE	0	48 T _{CLCL}	

EPROM Programming and Verification Waveforms

Figure 22. EPROM Programming and Verification Waveforms



^{* 8}KB: up to P2.4, 16KB: up to P2.5, 32KB: up to P3.4, 64KB: up to P3.5

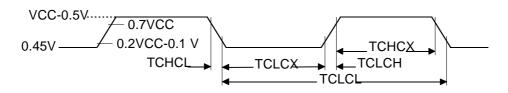
External Clock Drive Characteristics (XTAL1)

Table 36. AC Parameters

Symbol	Parameter	Min	Max	Units
T _{CLCL}	Oscillator Period	25		ns
T _{CHCX}	High Time	5		ns
T _{CLCX}	Low Time	5		ns
T _{CLCH}	Rise Time		5	ns
T _{CHCL}	Fall Time		5	ns
T _{CHCX} /T _{CLCX}	Cyclic ratio in X2 mode	40	60	%

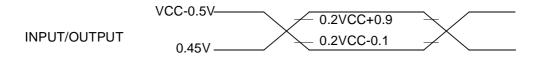
External Clock Drive Waveforms

Figure 23. External Clock Drive Waveforms



AC Testing Input/Output Waveforms

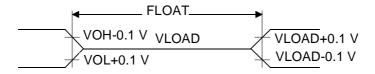
Figure 24. AC Testing Input/Output Waveforms



AC inputs during testing are driven at V_{CC} - 0.5 for a logic "1" and 0.45V for a logic "0". Timing measurement are made at V_{IH} min for a logic "1" and V_{IL} max for a logic "0".

Float Waveforms

Figure 25. Float Waveforms



For timing purposes a port pin is no longer floating when a 100 mV change from load voltage occurs and begins to float when a 100 mV change from the loaded V_{OH}/V_{OL} level occurs. $I_{OL}/I_{OH} \ge \pm$ 20mA.





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